

L Number	Hits	Search Text	DB	Time stamp
1	369	((inspect\$4 with (hole or openings)) and (semiconductor or sample or wafer) and ((electron or (charged adj particle) or charged-particle) near beam))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 20:41
2	19	((inspect\$4 with (hole or openings)) and (semiconductor or sample or wafer) and ((electron or (charged adj particle) or charged-particle) near beam)) and ((detect\$4 or measur\$7) with current with ground)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 20:42
5	2	(((((inspect\$4 with (hole or openings)) and (semiconductor or sample or wafer) and ((electron or (charged adj particle) or charged-particle) near beam)) and ((detect\$4 or measur\$7) with current with ground)) and (brightness or brightness-based)) and (display\$4)) and (current nearl distribut\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 20:44
6	2	(((((inspect\$4 with (hole or openings)) and (semiconductor or sample or wafer) and ((electron or (charged adj particle) or charged-particle) near beam)) and ((detect\$4 or measur\$7) with current with ground)) and (brightness or brightness-based)) and (display\$4)) and map\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 20:45
4	7	(((((inspect\$4 with (hole or openings)) and (semiconductor or sample or wafer) and ((electron or (charged adj particle) or charged-particle) near beam)) and ((detect\$4 or measur\$7) with current with ground)) and (brightness or brightness-based)) and (display\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 20:45
7	16	((inspect\$4 with (hole or openings)) and (semiconductor or sample or wafer) and ((electron or (charged adj particle) or charged-particle) near beam)) and ((detect\$4 or measur\$7) with current with ground)) and (bright\$4 or brightness-based)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 20:49
3	7	((inspect\$4 with (hole or openings)) and (semiconductor or sample or wafer) and ((electron or (charged adj particle) or charged-particle) near beam)) and ((detect\$4 or measur\$7) with current with ground)) and (brightness or brightness-based)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 20:49